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1. Name of conveying party(ies):

The Regents of the University of California

Additional name(s) of conveying party(ies) attached? ☐ Yes ☒ No

2. Name and address of receiving party(ies):

Name: EUV LLC

Address: Intel Corporation Mail Stop SCI-01

2200 Mission College Blvd.

Santa Clara, CA 95054

Additional name(s) & address(es) attached? ☐ Yes ☒ No

3. Nature of conveyance:

☒ Assignment ☐ Merger
☐ Security Agreement ☐ Change of Name
☐ Other _____

Execution Date: 12/17/2003

4. Application number(s) or patent number(s):

A. Patent Application No.:

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C. Patent No(s):

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Additional numbers attached? ☐ Yes ☒ No

If this document is being filed together with a new application, the execution date of the application is: _____

5. Name and address of party to whom correspondence concerning document should be mailed:

Name: Charles H. Jew

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6. Total Number of applications and patents involved: 25 X \$40.00 each

7. Total fee (37 CFR 3.41).....\$ 1000.00

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8. Fee Authorization. Authorization is given to charge any additional fees or credit any overpayment to Deposit Account No. 06-1325.

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9. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Charles H. Jew

Attorney (Reg. No.: 34,192)

Signature

Date

10. Total number of pages to be recorded: 3 (1 page cover sheet and 2 page document).

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ASSIGNMENT

Pursuant and subject to the EUV Intellectual Property Agreement, LBNL BG 97-217, ASSIGNOR(S) The Regents of The University of California, having received assignments from the inventors named below:

1. Erik H Anderson	2. David T Attwood	3. Phillip J Batoon	4. Jeffrey Bokor	5. Paul E Denham
6. Kenneth A Goldberg	7. Songtae Jaong	8. Michael Jones	9. Yun Lin	10. Patrick P Naulleau
11. David B Richardson	12. Edita Tejnil	13. James Underwood		

hereby sells, assign(s) and transfer(s) to ASSIGNEE, EUV LLC, a California Corporation, having its statewide administrative offices located at Intel Corporation Mail Stop SC1-01, 2200 Mission College Blvd., Santa Clara, CA 95054 and the successors, assigns and legal representatives of the ASSIGNEE all of its right, title and interest for the United States and its territorial possessions and in all foreign countries in and to, any and all improvements which are disclosed in the inventions as entitled, and which are found in the following with the above listed inventors:

US Application Filed:

LBNL. No.	Title	US Serial No.	File Date
CIB-1572	Method and Apparatus for Inspecting an EUV Mask Blank	09/902,502	7/9/2001
CIB-1573	Dual-Domain Lateral Shearing Interferometer	09/832,831	8/14/2000
CIB-1659	Method of Fabricating Reflection-Mode EUV Diffusers	09/846,150	4/30/2001
CIB-1660	Apparatus for Generating Partially Coherent Radiation	09/844,391	8/30/2001
CIB-1681	A Holographic Illuminator for Synchrotron-Based Projection Lithography Systems	09/981,500	10/16/2001
CIB-1689	A Synchrotron based EUV Lithography Illuminator Simulator	10/163,479	6/5/2002
CIB-1897	Diffractive Optical Element for Extreme Ultraviolet Wavefront Control	09/956,180	9/17/2001
CIB-1786	Apparatus for Generating Partially Coherent Radiation	10/377,947	2/28/2003
CIB-1808	An Extended Surface Parallel Coating Inspection Method	10/689,171	10/20/2003

US Patent Issued:

LBNL. No.	Title	US Patent No.	Issue Date
CIB-1392	Null Test Fourier Domain Alignment Technique for Phase-Shifting Point Diffraction Interferometer	6,111,846	8/29/2000
CIB-1397	Phase-Shifting Point Diffraction Interferometer Mask Designs	6,307,635	10/23/2001
CIB-1400	Graphical User Interface for Image Acquisition and Processing	6,341,183	1/22/2002
CIB-1407	Method and Apparatus for Inspecting Reflection Masks for Defects	6,555,828	4/29/2003
CIB-1409	Phase-Shifting Point Diffraction Interferometer Grating Designs	6,195,169	2/27/2001
CIB-1410	Phase-Shifting Point Diffraction Interferometer Focus-Aid Enhanced Mask	6,151,116	11/21/2000
CIB-1424	Method and Apparatus for Interferometric At-Wavelength Distortion Measurement Method	6,550,952	5/6/2003
CIB-1427	Dual Domain Phase-Shifting Point Diffraction Interferometer	6,100,978	8/8/2000
CIB-1438	In Situ alignment system for phase-shifting point-diffraction interferometry	6,118,535	9/12/2000
CIB-1445	Fourier-transform and Global Contrast Interferometer Alignment Methods	6,239,878	5/28/2001
CIB-1449	Phase-Shifting Point Diffraction Interferometer Phase Grating Designs	6,266,147	7/24/2001
CIB-1476	Interferometric at-wavelength flare characterization of EUV optical systems	6,233,058	8/15/2001
CIB-1531	Multi-level Scanning Schema for Defect Inspection	6,484,306	11/19/2002
CIB-1557	Miniature Self-Contained, Vacuum-Compatible Electronic Imaging Microscope	6,327,102	12/4/2001
CIB-1577	Hybrid Shearing and Phase-shifting point diffraction Interferometer	6,573,997	6/3/2003
CIB-1629	Method of Fabricating reflection-mode EUV diffraction elements	6,392,792	5/21/2002

and any legal equivalent thereof in a foreign country, including the right to claim priority and, in and to, all Letters Patent to be obtained for said invention by the above application or any continuation, division, continuation-in-part, extension or substitute thereof, and any reissue, reexamination or extension of said Letters Patent and all rights under all International Conventions for the Protection of Industrial Property;

ASSIGNOR(S) hereby covenants that no assignment, sale, agreement or encumbrance has been or will be made or entered into which would conflict with this assignment;

ASSIGNOR(S) further covenants that ASSIGNEE will, upon its request, be provided promptly with all pertinent facts and documents relating to said invention and said Letters Patent and legal equivalents as may be known and accessible to ASSIGNOR and will testify as to the same in any interference, litigation, or proceeding relating thereto and will promptly execute and deliver to ASSIGNEE or its legal representative any and all papers, instruments or affidavits required to apply for, obtain, maintain, issue or enforce said application, said invention and said Letters Patent and said equivalents thereof which may be necessary or desirable to carry out the purposes thereof. Any attorney of record is authorized and requested by the execution of this assignment to insert into this assignment the filing date and serial number of said application when officially known.

AND the ASSIGNOR(S) requests the Commissioner of Patents and Trademarks to issue said Letters Patent of the United States and any reissue or extension thereof to the ASSIGNEE, EUV LLC.

Executed this:

Signature

17th day of December, 2003

Dan Aletan, Patent Manager
The Regents of the University of California

TOTAL P.03

RECORDED: 05/05/2004

PATENT
REEL: 014601 FRAME: 0345